		449 (Modified) U.S Dept. of Commerce			· ·			Appln. No.		
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KF	AA	5,371,373	12/06/94	Shibata, et al.		250	492.22	22 11/16/93		
KK	BB	5,852,443	12/22/98	Kenworthy		345	431	06/2	06/27/96	
KF	CC	6,035,113	03/07/00	Gerber et al.		395	500.2	01/0	01/05/98	
rF	DD	5,533,170	07/02/96	Teitzel et al.		358	001.8	11/2	11/22/94	
KF	EE	5,239,624	08/24/93	Cook et al.		395	125	04/1	04/17/91	
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			ОТН	HER DOCUME	NTS	·	•			
	GG	Johansson,	C., et al., "S	Scalable Patter	n Generato	or Data	Path – F	or the		
Y.F	Future," 8 pages (2000).									
	НН	Buck, P., et	al., <i>"Integra</i>	tion of the Mic	ronic Omeg	ga6500	into the I	Mask		
KF		Manufacturir	ng Environr	ment," 9 pages	(2000).					
Examiner		<u> </u>		D	ate Consid	ered				
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